



# DRIP XVIII

18th CONFERENCE ON  
DEFECTS-RECOGNITION,  
IMAGING AND PHYSICS  
IN SEMICONDUCTORS

08-12 SEPTEMBER, 2019  
BERLIN, GERMANY



organized by

**FBH**  
Ferdinand-Braun-Institut  
Leibniz-Institut für  
Höchstfrequenztechnik

and

**IKZ**  
Leibniz Institute  
for Crystal Growth



[drip18.fbh-berlin.de](http://drip18.fbh-berlin.de)



[drip18@fbh-berlin.de](mailto:drip18@fbh-berlin.de)

## Materials

- Wide band-gap materials (SiC, group III-nitrides, ZnO)
- Group IV semiconductors (Si, Ge, diamond, etc.)
- III-V compound semiconductors (GaAs, InP, ternary and diluted magnetic materials)
- Materials for oxide electronics
- Photovoltaic materials
- Nanomaterials
- Novel device structures
- Novel 2D semiconductors

## Topics

- Recognition, Imaging and Physics of point and extended defects in semiconductors
- Diagnostics techniques of crystal growth and processing of semiconductor materials
- Device imaging and mapping for performance and reliability evaluation
- Defect and degradation analysis in optoelectronic and electronic devices
- Imaging techniques and instruments (scanning microscopies, X-ray, electron beam, noncontact electrical, optical and thermal imaging techniques)
- New frontiers of atomic-scale defect assessment (STM, AFM, SNOM, TEM, etc.)
- Multi-dimensional characterization with nano-scale space resolution (spectroscopic, X-ray, etc.)

## Conference Chairs

Dr. Anna Mogilatenko

Ferdinand-Braun-Institut,

Leibniz-Institut für Höchstfrequenztechnik

Prof. Dr. Matthias Bickermann

Leibniz Institute of Crystal Growth

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